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June 5, 2006

Applicants : Ryoko KITANO et al  
For : COOL AIR COOLING DEVICE FOR OPTICAL DISKS

PCT International Application No.: PCT/JP2004/018351

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U.S. Application No.

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Atty. Docket No.: 4414.P0692US

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Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

# INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(e)(1) and 1.98, enclosed herewith is a copy of the International Search Report, Form PTO-1449 and the references cited thereon. The relevance of these references is explained on the enclosed search report. Accordingly, further comment at this point in time should not be necessary.

Respectfully submitted,

  
Terryence F. Chapman

TFC/smd

FLYNN, THIEL, BOUTELL  
& TANIS, P.C.  
2026 Rambling Road  
Kalamazoo, MI 49008-1631  
Phone: (269) 381-1156  
Fax: (269) 381-5465

Dale H. Thiel	Reg. No. 24 323
David G. Boutell	Reg. No. 25 072
Terryence F. Chapman	Reg. No. 32 549
Mark L. Maki	Reg. No. 36 589
Liane L. Churney	Reg. No. 40 694
Brian R. Tumm	Reg. No. 36 328
Steven R. Thiel	Reg. No. 53 685
Donald J. Wallace	Reg. No. 43 977
Sidney B. Williams, Jr.	Reg. No. 24 949

Encl: International Search Report  
Form PTO-1449 and one copy of each listed reference

336.05/03

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /J.L./

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INFORMATION  
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## U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant
	AA			
	AB			
	AC			
	AD			
	AE			
	AF			
	AG			
	AH			
	AI			
	AJ			
	AK			

## FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Country Code - Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Trans.
	AL	JP 2000-235741	08-29-2000	AOKI et al	Abstract
	AM	JP 2003-132590	05-09-2003	INATANI et al	Abstract
	AN	JP 2002-092967	03-29-2002	KITANO et al	Abstract
	AO	JP 2000-137931	05-16-2000	SUGIYAMA et al	Abstract
	AP				

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	(Include Author, Title, Date, Pages, Etc.)
	AQ	
	AR	
EXAMINER SIGNATURE		DATE CONSIDERED
/Justin Loffredo/		10/15/2008

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